

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/796,608	LEE ET AL.
	<b>Examiner</b> B. Clayton McCraw	<b>Art Unit</b> 3744

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Consulted with Primary Examiner, William Doerrler	3/31/2006	BCM
Consulted with Primary Examiner, Melvin Jones	3/31/2006	BCM
Conducted inventor name search	3/31/2006	BCM
EAST Search notes attached	3/31/2006	BCM
EAST Interference search attached	3/31/2006	BCM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Sce A	Hatched	3/31/2006	BCM